

3100 U.S. PTO
10/000710

501/20



PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APP. NO.	FILED DATE	CLASS	SUBCLASS	GAU	EXAMINER
10080710	02/25/2002	365		281E	
**APPLICANTS: Park Sang-Mun, Joo, Kwon Hyeok					
**CONTINUING DATA VERIFIED: <i>no</i>					
** FOREIGN APPLICATIONS VERIFIED: <i>yes LP</i> REPUBLIC OF KOREA 2001-10097 02/27/2001					
PG-PUB. DATA PUBLISHED <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claims		SEARCHED BY LOOKING INC.			
US USD 110-000000-000000		F 2001-10097-02-27-001			
TITLE: System of performing a repair analysis for a semiconductor module circuit having a redundant architecture					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drawn	Figs. Drawn
		Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner PREPARED FOR ISSUE Application Examiner	
WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.			

FILED WITH:

☐ DISK (CRF)

☐ CD-ROM
(Attached in pocket on right inside flap)